



(11)

EP 3 298 390 B8

(12) **CORRECTED EUROPEAN PATENT SPECIFICATION**

(15) Correction information:
Corrected version no 1 (W1 B1)
Corrections, see
Bibliography INID code(s) 73

(51) International Patent Classification (IPC):
G01N 21/64 ^(2006.01) **G01N 21/95** ^(2006.01)
G06T 7/00 ^(2017.01) **H04N 5/374** ^(2011.01)
H04N 5/367 ^(2011.01)

(48) Corrigendum issued on:
16.02.2022 Bulletin 2022/07

(52) Cooperative Patent Classification (CPC):
G01N 21/6489; G01N 21/6456; G01N 21/9501;
G01N 21/9505; G01N 2021/646

(45) Date of publication and mention
of the grant of the patent:
07.07.2021 Bulletin 2021/27

(86) International application number:
PCT/US2016/029821

(21) Application number: **16890862.2**

(87) International publication number:
WO 2017/142569 (24.08.2017 Gazette 2017/34)

(22) Date of filing: **28.04.2016**

(54) **MICRO PHOTOLUMINESCENCE IMAGING WITH OPTICAL FILTERING**
MIKROPHOTOLUMINESZENZBILDGEBUNG MIT OPTISCHER FILTRIERUNG
IMAGERIE PAR MICROPHOTOLUMINESCENCE AVEC FILTRAGE OPTIQUE

(84) Designated Contracting States:
AL AT BE BG CH CY CZ DE DK EE ES FI FR GB
GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO
PL PT RO RS SE SI SK SM TR

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(30) Priority: **04.05.2015 US 201514703692**
09.10.2015 US 201514879522

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(43) Date of publication of application:
28.03.2018 Bulletin 2018/13

(60) Divisional application:
21183872.7

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